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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

E·XFI

Details	
Product Status	Active
Number of LABs/CLBs	768
Number of Logic Elements/Cells	·
Total RAM Bits	·
Number of I/O	113
Number of Gates	12000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx08a-2tqg144i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Temperature Grade Offering

Package	A54SX08A	A54SX16A	A54SX32A	A54SX72A
PQ208	C,I,A,M	C,I,A,M	C,I,A,M	C,I,A,M
TQ100	C,I,A,M	C,I,A,M	C,I,A,M	
TQ144	C,I,A,M	C,I,A,M	C,I,A,M	
TQ176			C,I,M	
BG329			C,I,M	
FG144	C,I,A,M	C,I,A,M	C,I,A,M	
FG256		C,I,A,M	C,I,A,M	C,I,A,M
FG484			C,I,M	C,I,A,M
CQ208			C,M,B	C,M,B
CQ256			C,M,B	C,M,B

Notes:

1. C = Commercial

- 2. I = Industrial
- 3. A = Automotive
- 4. M = Military
- 5. B = MIL-STD-883 Class B

6. For more information regarding automotive products, refer to the SX-A Automotive Family FPGAs datasheet.

7. For more information regarding Mil-Temp and ceramic packages, refer to the HiRel SX-A Family FPGAs datasheet.

Speed Grade and Temperature Grade Matrix

	F	Std	-1	-2	-3
Commercial	✓	1	1	1	Discontinued
Industrial		1	1	1	Discontinued
Automotive		1			
Military		1	1		
MIL-STD-883B		1	1		

Notes:

1. For more information regarding automotive products, refer to the SX-A Automotive Family FPGAs datasheet.

2. For more information regarding Mil-Temp and ceramic packages, refer to the HiRel SX-A Family FPGAs datasheet.

Contact your Actel Sales representative for more information on availability.

Routing Resources

The routing and interconnect resources of SX-A devices are in the top two metal layers above the logic modules (Figure 1-1 on page 1-1), providing optimal use of silicon, thus enabling the entire floor of the device to be spanned with an uninterrupted grid of logic modules. Interconnection between these logic modules is achieved using the Actel patented metal-to-metal programmable antifuse interconnect elements. The antifuses are normally open circuits and, when programmed, form a permanent low-impedance connection.

Clusters and SuperClusters can be connected through the use of two innovative local routing resources called FastConnect and DirectConnect, which enable extremely fast and predictable interconnection of modules within Clusters and SuperClusters (Figure 1-5 on page 1-4 and Figure 1-6 on page 1-4). This routing architecture also dramatically reduces the number of antifuses required to complete a circuit, ensuring the highest possible performance, which is often required in applications such as fast counters, state machines, and data path logic. The interconnect elements (i.e., the antifuses and metal tracks) have lower capacitance and lower resistance than any other device of similar capacity, leading to the fastest signal propagation in the industry.

DirectConnect is a horizontal routing resource that provides connections from a C-cell to its neighboring R-Cell in a given SuperCluster. DirectConnect uses a hardwired signal path requiring no programmable interconnection to achieve its fast signal propagation time of less than 0.1 ns.

FastConnect enables horizontal routing between any two logic modules within a given SuperCluster, and vertical routing with the SuperCluster immediately below it. Only one programmable connection is used in a FastConnect path, delivering a maximum pin-to-pin propagation time of 0.3 ns.

In addition to DirectConnect and FastConnect, the architecture makes use of two globally oriented routing resources known as segmented routing and high-drive routing. The Actel segmented routing structure provides a variety of track lengths for extremely fast routing between SuperClusters. The exact combination of track lengths and antifuses within each path is chosen by the 100% automatic place-and-route software to minimize signal propagation delays.

The general system of routing tracks allows any logic module in the array to be connected to any other logic or I/O module. Within this system, most connections typically require three or fewer antifuses, resulting in fast and predictable performance.

The unique local and general routing structure featured in SX-A devices allows 100% pin-locking with full logic utilization, enables concurrent printed circuit board (PCB) development, reduces design time, and allows designers to achieve performance goals with minimum effort.

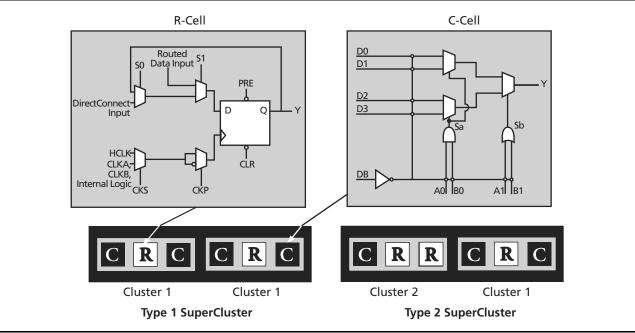


Figure 1-4 • Cluster Organization



Boundary-Scan Testing (BST)

All SX-A devices are IEEE 1149.1 compliant and offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. The BST function is controlled through the special JTAG pins (TMS, TDI, TCK, TDO, and TRST). The functionality of the JTAG pins is defined by two available modes: Dedicated and Flexible. TMS cannot be employed as a user I/O in either mode.

Dedicated Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, the user must reserve the JTAG pins in Actel's Designer software. Reserve the JTAG pins by checking the **Reserve JTAG** box in the Device Selection Wizard (Figure 1-12).

The default for the software is Flexible mode; all boxes are unchecked. Table 1-5 lists the definitions of the options in the Device Selection Wizard.

Flexible Mode

In Flexible mode, TDI, TCK, and TDO may be employed as either user I/Os or as JTAG input pins. The internal resistors on the TMS and TDI pins are not present in flexible JTAG mode.

To select the Flexible mode, uncheck the **Reserve JTAG** box in the Device Selection Wizard dialog in the Actel Designer software. In Flexible mode, TDI, TCK, and TDO pins may function as user I/Os or BST pins. The functionality is controlled by the BST Test Access Port (TAP) controller. The TAP controller receives two control inputs, TMS and TCK. Upon power-up, the TAP controller enters the Test-Logic-Reset state. In this state, TDI, TCK, and TDO function as user I/Os. The TDI, TCK, and TDO are transformed from user I/Os into BST pins when a rising edge on TCK is detected while TMS is at logic low. To return to Test-Logic Reset state, TMS must be high for at least five TCK cycles. **An external 10 k pull-up resistor to V_{CCI} should be placed on the TMS pin to pull it High by default.**

Table 1-6 describes the different configuration requirements of BST pins and their functionality in different modes.

Table 1-6 •	Boundary-Scan Pin Configurations and
	Functions

Mode	Designer "Reserve JTAG" Selection	TAP Controller State
Dedicated (JTAG)	Checked	Any
Flexible (User I/O)	Unchecked	Test-Logic-Reset
Flexible (JTAG)	Unchecked	Any EXCEPT Test- Logic-Reset

Figure 1-12 • Device Selection Wizard

Table 1-5 • Reserve Pin Definitions

Pin	Function				
Reserve JTAG	Keeps pins from being used and changes the behavior of JTAG pins (no pull-up on TMS)				
Reserve JTAG Test Reset	Regular I/O or JTAG reset with an internal pull-up				
Reserve Probe	Keeps pins from being used or regular I/O				

TRST Pin

The TRST pin functions as a dedicated Boundary-Scan Reset pin when the **Reserve JTAG Test Reset** option is selected as shown in Figure 1-12. An internal pull-up resistor is permanently enabled on the TRST pin in this mode. Actel recommends connecting this pin to ground in normal operation to keep the JTAG state controller in the Test-Logic-Reset state. When JTAG is being used, it can be left floating or can be driven high.

When the **Reserve JTAG Test Reset** option is not selected, this pin will function as a regular I/O. If unused as an I/O in the design, it will be configured as a tristated output.

Pin Description

CLKA/B, I/O Clock A and B

These pins are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. The clock input is buffered prior to clocking the R-cells. When not used, this pin must be tied Low or High (NOT left floating) on the board to avoid unwanted power consumption.

For A54SX72A, these pins can also be configured as user I/Os. When employed as user I/Os, these pins offer builtin programmable pull-up or pull-down resistors active during power-up only. When not used, these pins must be tied Low or High (NOT left floating).

QCLKA/B/C/D, I/O Quadrant Clock A, B, C, and D

These four pins are the quadrant clock inputs and are only used for A54SX72A with A, B, C, and D corresponding to bottom-left, bottom-right, top-left, and top-right quadrants, respectively. They are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. Each of these clock inputs can drive up to a quarter of the chip, or they can be grouped together to drive multiple quadrants. The clock input is buffered prior to clocking the R-cells. When not used, these pins must be tied Low or High on the board (NOT left floating).

These pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only.

GND Ground

Low supply voltage.

HCLK Dedicated (Hardwired) Array Clock

This pin is the clock input for sequential modules. Input levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. When not used, HCLK must be tied Low or High on the board (NOT left floating). When used, this pin should be held Low or High during power-up to avoid unwanted static power consumption.

I/O Input/Output

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI or 5 V PCI specifications. Unused I/O pins are automatically tristated by the Designer software.

NC No Connection

This pin is not connected to circuitry within the device and can be driven to any voltage or be left floating with no effect on the operation of the device.

PRA/B, I/O Probe A/B

The Probe pin is used to output data from any userdefined design node within the device. This independent diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK, I/O Test Clock

Test clock input for diagnostic probe and device programming. In Flexible mode, TCK becomes active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI, I/O Test Data Input

Serial input for boundary scan testing and diagnostic probe. In Flexible mode, TDI is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO, I/O Test Data Output

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state. When Silicon Explorer II is being used, TDO will act as an output when the checksum command is run. It will return to user /IO when checksum is complete.

TMS Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO, TRST). In flexible mode when the TMS pin is set Low, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-6 on page 1-9). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the logic reset state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The logic reset state is reached five TCK cycles after the TMS pin is set High. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

TRST, I/O Boundary Scan Reset Pin

Once it is configured as the JTAG Reset pin, the TRST pin functions as an active low input to asynchronously initialize or reset the boundary scan circuit. The TRST pin is equipped with an internal pull-up resistor. This pin functions as an I/O when the **Reserve JTAG Reset Pin** is not selected in Designer.

V_{CCI} Supply Voltage

Supply voltage for I/Os. See Table 2-2 on page 2-1. All V_{CCI} power pins in the device should be connected.

V_{CCA} Supply Voltage

Supply voltage for array. See Table 2-2 on page 2-1. All V_{CCA} power pins in the device should be connected.

Electrical Specifications

Table 2-5 • 3.3 V LVTTL and 5 V TTL Electrical Specifications

			Comm	ercial	Indus	strial	
Symbol	Parameter		Min.	Max.	Min.	Max.	Units
V _{OH}	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	$(I_{OH} = -1 \text{ mA})$	0.9 V _{CCI}		0.9 V _{CCI}		V
	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OH} = -8 mA)	2.4		2.4		V
V _{OL}	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 1 mA)		0.4		0.4	V
	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 12 mA)		0.4		0.4	V
V _{IL}	Input Low Voltage			0.8		0.8	V
V _{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μA
I _{OZ}	Tristate Output Leakage Current		-10	10	-10	10	μΑ
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web	•).			•		

Note: *The IBIS model can be found at http://www.actel.com/download/ibis/default.aspx.

Table 2-6 • 2.5 V LVCMOS2 Electrical Specifications

			Comn	nercial	Indu	strial	
Symbol	Parameter		Min.	Max.	Min.	Max.	Units
V _{OH}	$V_{DD} = MIN,$ $V_{I} = V_{IH} \text{ or } V_{IL}$	$(I_{OH} = -100 \mu\text{A})$	2.1		2.1		V
	$V_{DD} = MIN,$ $V_{I} = V_{IH} \text{ or } V_{IL}$	(I _{OH} = -1 mA)	2.0		2.0		V
	$V_{DD} = MIN,$ $V_{I} = V_{IH} \text{ or } V_{IL}$	(I _{OH} =2 mA)	1.7		1.7		V
V _{OL}	$V_{DD} = MIN,$ $V_{I} = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 100 μA)		0.2		0.2	V
	$V_{DD} = MIN,$ $V_{I} = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 1 mA)		0.4		0.4	V
	$V_{DD} = MIN,$ $V_{I} = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 2 mA)		0.7		0.7	V
V _{IL}	Input Low Voltage, V _{OUT} ≤ V _{VOL(max)}		-0.3	0.7	-0.3	0.7	V
V _{IH}	Input High Voltage, V _{OUT} ≥ V _{VOH(min)}		1.7	5.75	1.7	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μΑ
I _{OZ}	Tristate Output Leakage Current, $V_{OUT} = V_{CCI}$ or GND		-10	10	-10	10	μΑ
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at http://www.actel.com/download/ibis/default.aspx.



PCI Compliance for the SX-A Family

The SX-A family supports 3.3 V and 5 V PCI and is compliant with the PCI Local Bus Specification Rev. 2.1.

Table 2-7 • DC Specifications (5 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V _{CCA}	Supply Voltage for Array		2.25	2.75	V
V _{CCI}	Supply Voltage for I/Os		4.75	5.25	V
V _{IH}	Input High Voltage		2.0	5.75	V
V _{IL}	Input Low Voltage		-0.5	0.8	V
I _{IH}	Input High Leakage Current ¹	V _{IN} = 2.7	-	70	μA
I _{IL}	Input Low Leakage Current ¹	V _{IN} = 0.5	-	-70	μA
V _{OH}	Output High Voltage	I _{OUT} = -2 mA	2.4	-	V
V _{OL}	Output Low Voltage ²	I _{OUT} = 3 mA, 6 mA	-	0.55	V
C _{IN}	Input Pin Capacitance ³		-	10	pF
C _{CLK}	CLK Pin Capacitance		5	12	pF

Notes:

1. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.

2. Signals without pull-up resistors must have 3 mA low output current. Signals requiring pull-up must have 6 mA; the latter includes FRAME#, IRDY#, TRDY#, DEVSEL#, STOP#, SERR#, PERR#, LOCK#, and, when used AD[63::32], C/BE[7::4]#, PAR64, REQ64#, and ACK64#.

3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).



To determine the heat sink's thermal performance, use the following equation:

$$\theta_{JA(TOTAL)} = \theta_{JC} + \theta_{CS} + \theta_{SA}$$

EQ 2-14

where:

 $\theta_{CS} = 0.37^{\circ}C/W$

 thermal resistance of the interface material between the case and the heat sink, usually provided by the thermal interface manufacturer

 θ_{SA} = thermal resistance of the heat sink in °C/W

 $\theta_{SA} = \theta_{JA(TOTAL)} - \theta_{JC} - \theta_{CS}$ EQ 2-15 $\theta_{SA} = 13.33^{\circ}C/W - 3.20^{\circ}C/W - 0.37^{\circ}C/W$

$$\theta_{SA} = 9.76^{\circ}C/W$$

A heat sink with a thermal resistance of 9.76°C/W or better should be used. Thermal resistance of heat sinks is a function of airflow. The heat sink performance can be significantly improved with the presence of airflow.

Carefully estimating thermal resistance is important in the long-term reliability of an Actel FPGA. Design engineers should always correlate the power consumption of the device with the maximum allowable power dissipation of the package selected for that device, using the provided thermal resistance data.

Note: The values may vary depending on the application.

Table 2-22 A54SX16A Timing Characteristics

		-3 S	beed*	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated ((Hardwired) Array Clock Netwo	rks										
t _{нскн}	Input Low to High (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.1		1.2		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{HCKSW}	Maximum Skew		0.3		0.3		0.4		0.4		0.7	ns
t _{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f _{HMAX}	Maximum Frequency		357		294		263		227		167	MHz
Routed Arr	ay Clock Networks											
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.2		1.3		1.6		2.2	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: *All –3 speed grades have been discontinued.

Table 2-26 • A54SX16A Timing Characteristics

(Worst-Case Commercial Condition	$V_{CCA} = 2.25 \text{ V}, \text{ V}_{CCI} = 3.0 \text{ V}, \text{ T}_{\text{J}} = 70^{\circ}\text{C}$
----------------------------------	--------------------------------------------------------------------------------------------------------

		-3 Sp	beed ¹	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
3.3 V PCI O	utput Module Timing ²											
t _{DLH}	Data-to-Pad Low to High		2.0		2.3		2.6		3.1		4.3	ns
t _{DHL}	Data-to-Pad High to Low		2.2		2.5		2.8		3.3		4.6	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.4		1.7		1.9		2.2		3.1	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.0		2.3		2.6		3.1		4.3	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.2		3.8		5.3	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.2		2.5		2.8		3.3		4.6	ns
d_{TLH}^{3}	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d _{THL} ³ Delta High to Low			0.015		0.015		0.015		0.015		0.025	ns/pF
3.3 V LVTTL	Output Module Timing ⁴											
t _{DLH}	Data-to-Pad Low to High		2.8		3.2		3.6		4.3		6.0	ns
t _{DHL}	Data-to-Pad High to Low		2.7		3.1		3.5		4.1		5.7	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		9.5		10.9		12.4		14.6		20.4	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.2		2.6		2.9		3.4		4.8	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		15.8		18.9		21.3		25.4		34.9	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.8		3.2		3.6		4.3		6.0	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.9		3.3		3.7		4.4		6.2	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.7		3.1		3.5		4.1		5.7	ns
d_{TLH}^{3}	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d_{THL}^{3}	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.053		0.053		0.067		0.073		0.107	ns/pF

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 10 pF loading and 25 Ω resistance.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = (0.1* V_{CCI} - 0.9* V_{CCI} / (C_{load} * $d_{T[LH|HL|HLS]}$) where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

4. Delays based on 35 pF loading.

Table 2-28 • A54SX32A Timing Characteristics

(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

		-3 S	beed ¹	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
C-Cell Propa	agation Delays ²			- 		-		- 		-		<u> </u>
t _{PD}	Internal Array Module		0.8		0.9		1.1		1.2		1.7	ns
Predicted R	outing Delays ³											
t _{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t _{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t _{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.6	ns
t _{RD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t _{RD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t _{RD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t _{RD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t _{RD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns
R-Cell Timin	Ig											<u>.</u>
t _{RCO}	Sequential Clock-to-Q		0.6		0.7		0.8		0.9		1.3	ns
t _{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.6		0.8		1.0	ns
t _{PRESET}	Asynchronous Preset-to-Q		0.6		0.7		0.7		0.9		1.2	ns
t _{sud}	Flip-Flop Data Input Set-Up	0.6		0.7		0.8		0.9		1.2		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.2		1.4		1.5		1.8		2.5		ns
t _{recasyn}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Pulse Width	1.4		1.6		1.8		2.1		2.9		ns
Input Modu	le Propagation Delays											-
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.6		0.7		0.8		0.9		1.2	ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		1.2		1.3		1.5		1.8		2.5	ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI		0.5		0.6		0.6		0.7		1.0	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.6		0.7		0.8		0.9		1.3	ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.8		0.9		1.0		1.2		1.6	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.4		1.6		1.8		2.2		3.0	ns

Notes:

1. All –3 speed grades have been discontinued.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-30 • A54SX32A Timing Characteristics

(Worst-Case Commercial Conditions	V _{CCA} = 2.25 V, V _{CCI} = 3.0 V, T _J = 70°C)
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		-3 S	beed*	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated	(Hardwired) Array Clock Netwo	rks										<u> </u>
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{HPVVL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f _{HMAX} Maximum Frequency			357		313		278		238		172	MHz
Routed Arr	ay Clock Networks											
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.6	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.4		2.7		3.2		4.5	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.3		2.7		3.1		3.6		5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.5		2.9		3.4		4.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.4		2.8		3.2		3.7		5.2	ns
t _{rckl}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.1	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.9		1.0		1.2		1.4		1.9	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.4		1.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-38 • A54SX72A Timing Characteristics (Continued)

(Worst-Case Commercial Conditions $V_{CCA} = 2.25 \text{ V}$, $V_{CCI} = 4.75 \text{ V}$, $T_J = 70^{\circ}\text{C}$)

		-3 Sp	beed*	-2 S	peed	-1 S	peed	Std. 9	Speed	–F S	peed	
Parameter	Description	Min. Max		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.4	ns
t _{qchkl}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.5	ns
t _{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t _{qcksw}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t _{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-41 • A54SX72A Timing Characteristics

(Worst-Case Commercial Conditions	$V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_{J} = 70^{\circ}C$
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		-3 Sp	beed ¹	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
5 V PCI Out	put Module Timing ²									•		
t _{DLH}	Data-to-Pad Low to High		2.7		3.1		3.5		4.1		5.7	ns
t _{DHL}	Data-to-Pad High to Low		3.4		3.9		4.4		5.1		7.2	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.7		3.1		3.5		4.1		5.7	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.4		3.9		4.4		5.1		7.2	ns
d _{TLH} ³	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d _{THL} ³ Delta High to Low			0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Out	put Module Timing ⁴	•								•		
t _{DLH}	Data-to-Pad Low to High		2.4		2.8		3.1		3.7		5.1	ns
t _{DHL}	Data-to-Pad High to Low		3.1		3.5		4.0		4.7		6.6	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		7.4		8.5		9.7		11.4		15.9	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.1		3.7		5.1	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.1		3.5		4.0		4.7		6.6	ns
d _{TLH} ³	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}^{3}	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 50 pF loading.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = $(0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$ where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

4. Delays based on 35 pF loading.

	2	08-Pin PQF	P		208-Pin PQFP Pin A54SX08A A54SX16A A54SX32A							
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function			
1	GND	GND	GND	GND	36	I/O	I/O	I/O	I/O			
2	TDI, I/O	TDI, I/O	tdi, I/o	TDI, I/O	37	I/O	I/O	I/O	I/O			
3	I/O	I/O	I/O	I/O	38	I/O	I/O	I/O	I/O			
4	NC	I/O	I/O	I/O	39	NC	ΙΟ	I/O	I/O			
5	I/O	I/O	I/O	I/O	40	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}			
6	NC	I/O	I/O	I/O	41	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}			
7	I/O	I/O	I/O	I/O	42	I/O	I/O	I/O	I/O			
8	I/O	I/O	I/O	I/O	43	I/O	I/O	I/O	I/O			
9	I/O	I/O	I/O	I/O	44	I/O	I/O	I/O	I/O			
10	I/O	I/O	I/O	I/O	45	I/O	I/O	I/O	I/O			
11	TMS	TMS	TMS	TMS	46	I/O	I/O	I/O	I/O			
12	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	47	I/O	I/O	I/O	I/O			
13	I/O	I/O	I/O	I/O	48	NC	I/O	I/O	I/O			
14	NC	I/O	I/O	I/O	49	I/O	I/O	I/O	I/O			
15	I/O	I/O	I/O	I/O	50	NC	I/O	I/O	I/O			
16	I/O	I/O	I/O	I/O	51	I/O	I/O	I/O	I/O			
17	NC	I/O	I/O	I/O	52	GND	GND	GND	GND			
18	I/O	I/O	I/O	GND	53	I/O	I/O	I/O	I/O			
19	I/O	I/O	I/O	V _{CCA}	54	I/O	I/O	I/O	I/O			
20	NC	I/O	I/O	I/O	55	I/O	I/O	I/O	I/O			
21	I/O	I/O	I/O	I/O	56	I/O	I/O	I/O	I/O			
22	I/O	I/O	I/O	I/O	57	I/O	I/O	I/O	I/O			
23	NC	I/O	I/O	I/O	58	I/O	I/O	I/O	I/O			
24	I/O	I/O	I/O	I/O	59	I/O	I/O	I/O	I/O			
25	NC	NC	NC	I/O	60	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}			
26	GND	GND	GND	GND	61	NC	I/O	I/O	I/O			
27	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	62	I/O	I/O	I/O	I/O			
28	GND	GND	GND	GND	63	I/O	I/O	I/O	I/O			
29	I/O	I/O	I/O	I/O	64	NC	I/O	I/O	I/O			
30	TRST, I/O	trst, I/O	trst, I/O	TRST, I/O	65	I/O	I/O	NC	I/O			
31	NC	I/O	I/O	I/O	66	I/O	I/O	I/O	I/O			
32	I/O	I/O	I/O	I/O	67	NC	I/O	I/O	I/O			
33	I/O	I/O	I/O	I/O	68	I/O	I/O	I/O	I/O			
34	I/O	I/O	I/O	I/O	69	I/O	I/O	I/O	I/O			
35	NC	I/O	I/O	I/O	70	NC	I/O	I/O	I/O			

	2	08-Pin PQF	P			2	08-Pin PQF	P	
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
141	NC	I/O	I/O	I/O	176	NC	I/O	I/O	I/O
142	I/O	I/O	I/O	I/O	177	I/O	Ι/O	I/O	I/O
143	NC	I/O	I/O	I/O	178	I/O	I/O	I/O	QCLKD
144	I/O	I/O	I/O	I/O	179	I/O	I/O	I/O	I/O
145	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	180	CLKA	CLKA	CLKA	CLKA
146	GND	GND	GND	GND	181	CLKB	CLKB	CLKB	CLKB
147	I/O	I/O	I/O	I/O	182	NC	NC	NC	NC
148	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	183	GND	GND	GND	GND
149	I/O	I/O	I/O	I/O	184	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
150	I/O	I/O	I/O	I/O	185	GND	GND	GND	GND
151	I/O	I/O	I/O	I/O	186	PRA, I/O	PRA, I/O	PRA, I/O	PRA, I/O
152	I/O	I/O	I/O	I/O	187	I/O	I/O	I/O	V _{CCI}
153	I/O	I/O	I/O	I/O	188	I/O	I/O	I/O	I/O
154	I/O	I/O	I/O	I/O	189	NC	I/O	I/O	I/O
155	NC	I/O	I/O	I/O	190	I/O	I/O	I/O	QCLKC
156	NC	I/O	I/O	I/O	191	I/O	I/O	I/O	I/O
157	GND	GND	GND	GND	192	NC	I/O	I/O	I/O
158	I/O	I/O	I/O	I/O	193	I/O	I/O	I/O	I/O
159	I/O	I/O	I/O	I/O	194	I/O	I/O	I/O	I/O
160	I/O	I/O	I/O	I/O	195	NC	I/O	I/O	I/O
161	I/O	I/O	I/O	I/O	196	I/O	I/O	I/O	I/O
162	I/O	I/O	I/O	I/O	197	I/O	I/O	I/O	I/O
163	I/O	I/O	I/O	I/O	198	NC	I/O	I/O	I/O
164	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	199	I/O	I/O	I/O	I/O
165	I/O	I/O	I/O	I/O	200	I/O	I/O	I/O	I/O
166	I/O	I/O	I/O	I/O	201	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
167	NC	I/O	I/O	I/O	202	NC	I/O	I/O	I/O
168	I/O	I/O	I/O	I/O	203	NC	I/O	I/O	I/O
169	I/O	I/O	I/O	I/O	204	I/O	I/O	I/O	I/O
170	NC	I/O	I/O	I/O	205	NC	I/O	I/O	I/O
171	I/O	I/O	I/O	I/O	206	I/O	I/O	I/O	I/O
172	I/O	I/O	I/O	I/O	207	I/O	I/O	I/O	I/O
173	NC	I/O	I/O	I/O	208	TCK, I/O	TCK, I/O	TCK, I/O	TCK, I/O
174	I/O	I/O	I/O	I/O	L				
175	I/O	I/O	I/O	I/O					

	100-	TQFP			100-	TQFP	
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND	36	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O	37	NC	NC	NC
3	I/O	I/O	I/O	38	I/O	I/O	I/O
4	I/O	I/O	I/O	39	HCLK	HCLK	HCLK
5	I/O	I/O	I/O	40	I/O	I/O	I/O
6	I/O	I/O	I/O	41	I/O	I/O	I/O
7	TMS	TMS	TMS	42	I/O	I/O	I/O
8	V _{CCI}	V _{CCI}	V _{CCI}	43	I/O	I/O	I/O
9	GND	GND	GND	44	V _{CCI}	V _{CCI}	V _{CCI}
10	I/O	I/O	I/O	45	I/O	I/O	I/O
11	I/O	I/O	I/O	46	I/O	I/O	I/O
12	I/O	I/O	I/O	47	I/O	I/O	I/O
13	I/O	I/O	I/O	48	I/O	I/O	I/O
14	I/O	I/O	I/O	49	TDO, I/O	TDO, I/O	TDO, I/O
15	I/O	I/O	I/O	50	I/O	I/O	I/O
16	TRST, I/O	TRST, I/O	TRST, I/O	51	GND	GND	GND
17	I/O	I/O	I/O	52	I/O	I/O	I/O
18	I/O	I/O	I/O	53	I/O	I/O	I/O
19	I/O	I/O	I/O	54	I/O	I/O	I/O
20	V _{CCI}	V _{CCI}	V _{CCI}	55	I/O	I/O	I/O
21	I/O	I/O	I/O	56	I/O	I/O	I/O
22	I/O	I/O	I/O	57	V _{CCA}	V _{CCA}	V _{CCA}
23	I/O	I/O	I/O	58	V _{CCI}	V _{CCI}	V _{CCI}
24	I/O	I/O	I/O	59	I/O	I/O	I/O
25	I/O	I/O	I/O	60	I/O	I/O	I/O
26	I/O	I/O	I/O	61	I/O	I/O	I/O
27	I/O	I/O	I/O	62	I/O	I/O	I/O
28	I/O	I/O	I/O	63	I/O	I/O	I/O
29	I/O	I/O	I/O	64	I/O	I/O	I/O
30	I/O	I/O	I/O	65	I/O	I/O	I/O
31	I/O	I/O	I/O	66	I/O	I/O	I/O
32	I/O	I/O	I/O	67	V _{CCA}	V _{CCA}	V _{CCA}
33	I/O	I/O	I/O	68	GND	GND	GND
34	PRB, I/O	PRB, I/O	PRB, I/O	69	GND	GND	GND
35	V _{CCA}	V _{CCA}	V _{CCA}	70	I/O	I/O	I/O

329-Pi	n PBGA	329-Pi	n PBGA	329-Pi	in PBGA	329-Pin PE	
Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function
D11	V _{CCA}	H1	I/O	L14	GND	P12	GND
D12	NC	H2	I/O	L20	NC	P13	GND
D13	I/O	H3	I/O	L21	I/O	P14	GND
D14	I/O	H4	I/O	L22	I/O	P20	I/O
D15	I/O	H20	V _{CCA}	L23	NC	P21	I/O
D16	I/O	H21	I/O	M1	I/O	P22	I/O
D17	I/O	H22	I/O	M2	I/O	P23	I/O
D18	I/O	H23	I/O	M3	I/O	R1	I/O
D19	I/O	J1	NC	M4	V _{CCA}	R2	I/O
D20	I/O	J2	I/O	M10	GND	R3	I/O
D21	I/O	J3	I/O	M11	GND	R4	I/O
D22	I/O	J4	I/O	M12	GND	R20	I/O
D23	I/O	J20	I/O	M13	GND	R21	I/O
E1	V _{CCI}	J21	I/O	M14	GND	R22	I/O
E2	I/O	J22	I/O	M20	V _{CCA}	R23	I/O
E3	I/O	J23	I/O	M21	I/O	T1	I/O
E4	I/O	К1	I/O	M22	I/O	T2	I/O
E20	I/O	К2	I/O	M23	V _{CCI}	Т3	I/O
E21	I/O	К3	I/O	N1	I/O	T4	I/O
E22	I/O	К4	I/O	N2	TRST, I/O	T20	I/O
E23	I/O	K10	GND	N3	I/O	T21	I/O
F1	I/O	K11	GND	N4	I/O	T22	I/O
F2	TMS	K12	GND	N10	GND	T23	I/O
F3	I/O	K13	GND	N11	GND	U1	I/O
F4	I/O	K14	GND	N12	GND	U2	I/O
F20	I/O	K20	I/O	N13	GND	U3	V _{CCA}
F21	I/O	K21	I/O	N14	GND	U4	I/O
F22	I/O	K22	I/O	N20	NC	U20	I/O
F23	I/O	K23	I/O	N21	I/O	U21	V _{CCA}
G1	I/O	L1	I/O	N22	I/O	U22	I/O
G2	I/O	L2	I/O	N23	I/O	U23	I/O
G3	I/O	L3	I/O	P1	I/O	V1	V _{CCI}
G4	I/O	L4	NC	P2	I/O	V2	I/O
G20	I/O	L10	GND	P3	I/O	V3	I/O
G21	I/O	L11	GND	P4	I/O	V4	I/O
G22	I/O	L12	GND	P10	GND	V20	I/O
G23	GND	L13	GND	P11	GND	V21	I/O



Datasheet Categories

In order to provide the latest information to designers, some datasheets are published before data has been fully characterized. Datasheets are designated as "Product Brief," "Advanced," "Production," and "Datasheet Supplement." The definitions of these categories are as follows:

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The product brief is a summarized version of a datasheet (advanced or production) containing general product information. This brief gives an overview of specific device and family information.

Advanced

This datasheet version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production.

Unmarked (production)

This datasheet version contains information that is considered to be final.

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